



# Product data sheet

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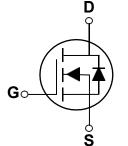
BSS138LT1G-MS



SOT-23

#### Features

- 50V,0.2A, RDS(ON) =1.3Ω@VGS=10V
- Improved dv/dt capability
- Fast switching
- Green Device Available



## Applications

- Motor Drive
- Power Tools
- LED Lighting

BVDSS	RDSON	ID
50V	1.3Ω	0.2A

#### Absolute Maximum Ratings Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	50	V
V <sub>GS</sub>	Gate-Source Voltage	±20	V
	Drain Current – Continuous (T <sub>A</sub> =25℃)	0.2	A
ID	Drain Current – Continuous (T <sub>A</sub> =70°C)	0.12	A
Ідм	Drain Current – Pulsed <sup>1</sup>	0.8	A
Power Dissipation (T <sub>A</sub> =25℃)		0.35	W
P <sub>D</sub>	Power Dissipation – Derate above 25℃	0.003	W/°C
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
R <sub>0JA</sub>	Thermal Resistance Junction to ambient		357	°C/W



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## Electrical Characteristics (TJ=25 °C, unless otherwise noted)

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS}$ =0V , I <sub>D</sub> =250uA	50			V
	Drain Courses Lookana Current	$V_{DS}$ =50V , $V_{GS}$ =0V , $T_{J}$ =25°C			1	uA
I <sub>DSS</sub> Drain-Source Leakage Current		$V_{DS}$ =40V , $V_{GS}$ =0V , $T_J$ =125°C			100	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±10	uA

#### **On Characteristics**

	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V , I <sub>D</sub> =0.2A		1.5	2.0	Ω
NDS(ON)		V <sub>GS</sub> =4.5V , I <sub>D</sub> =0.1A		2.0	3.5	Ω
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	0.8	1.1	1.6	V
gfs	Forward Transconductance	V <sub>DS</sub> =10V , I <sub>D</sub> =0.2A		0.5		S

#### **Dynamic and switching Characteristics**

Qg	Total Gate Charge <sup>2,3</sup>		 3.7	
Q <sub>gs</sub>	Gate-Source Charge <sup>2,3</sup>	$V_{DS}$ =30V , $V_{GS}$ =10V , $I_{D}$ =0.2A	 0.9	 nC
Q <sub>gd</sub>	Gate-Drain Charge <sup>2,3</sup>		 0.4	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2,3</sup>		 3	
Tr	Rise Time <sup>2,3</sup>	$V_{DD}$ =30V , $V_{GS}$ =10V , $R_{G}$ =6 $\Omega$	 5	 
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2,3</sup>	I <sub>D</sub> =0.2A	 14	 ns
Tf	Fall Time <sup>2,3</sup>		 9	
Ciss	Input Capacitance		 25.5	
Coss	Output Capacitance	V <sub>DS</sub> =30V , V <sub>GS</sub> =0V , F=1MHz	 17	 pF
Crss	Reverse Transfer Capacitance		 7.8	

## **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol Parameter		Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	────V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			0.2	А
lsм	Pulsed Source Current				0.4	A
Vsd	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =0.2A , T <sub>J</sub> =25℃			1.4	V
trr	Reverse Recovery Time	V <sub>R</sub> =50V, Is=0.2A		3.4		ns
Qrr	Reverse Recovery Charge	dl/dt=100A/µs, Tյ=25℃		0.7		nC

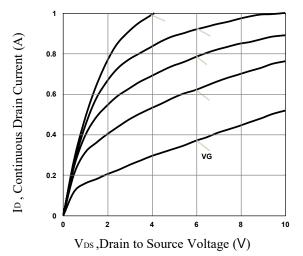
Note : 1. R

Repetitive Rating : Pulsed width limited by maximum junction temperature.

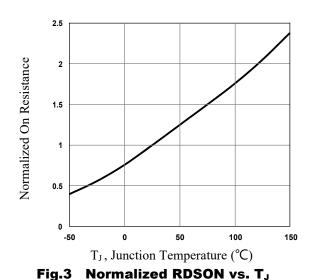
The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%. 2.

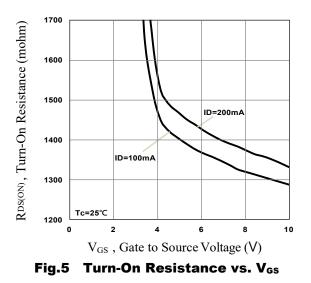
3. Essentially independent of operating temperature.

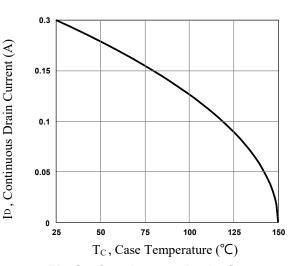












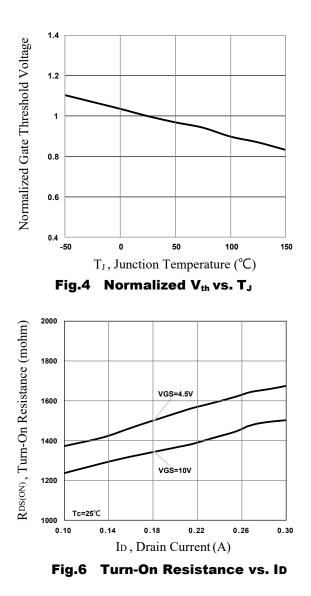
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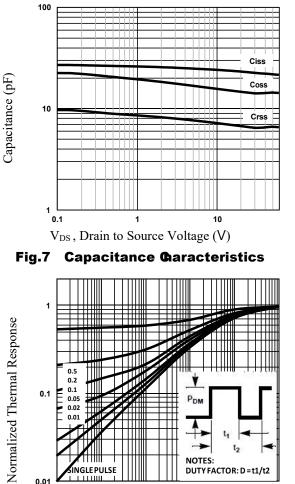
HF

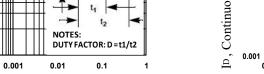
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Fig.2 Continuous Drain Current vs. Tc









Square Wave Pulse Duration (s)

**Fig.9 Normalized Transient** 

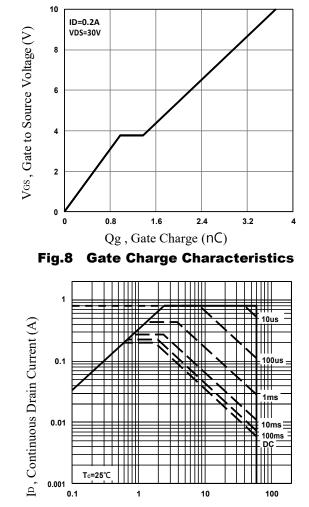
**INGLE PULSE** 

0.0001

111100

0.01

0.00001



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HF

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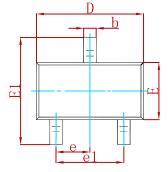
V<sub>DS</sub>, Drain to Source Voltage(V)

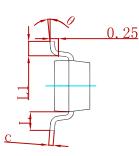
Fig.10 Maximum Safe Operation Area

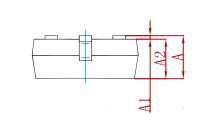


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## PACKAGE MECHANICAL DATA

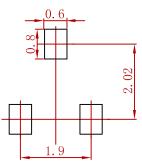






Symbol	Dimensions In Millimeters		Dimension	s in inches
Symbol	Min	Max	Min	Max
Α	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
e	0.950	) TYP	0.037	7 TYP
e1	1.800	2.000	0.071	0.079
L	0.550 REF		0.022	2 REF
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

## Suggested Pad Layout



Note:

Controlling dimension:in millimeters.
General tolerance:± 0.05mm.
The pad layout is for reference purposes only.

## **REEL SPECIFICATION**

P/N	PKG	QTY
BSS138LT1G-MS	SOT-23	3000
BSS138LT1G-MS	SOT-23	3000



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